(19) INDIA

(51) International

(86) International

(87) International

Publication No

Filing Date

Filing Date (62) Divisional to

Application Number

Filing Date

(61) Patent of Addition :NA

to Application Number :NA

Application No

classification

(22) Date of filing of Application :05/01/2023

(43) Publication Date: 13/01/2023

(54) Title of the invention : ANALYSIS OF THERMAL PROPERTIES OF ORGANIC SOLAR CELL AT DIFFERENT DEVICE TEMPERATURES

:H01L0051420000, H01L0051000000,

H01L0051440000, G06F0030330000,

H01B0001120000

:NA

:NA

: NA

:NA

:NA

(71)Name of Applicant:

1)Dr Narender Singh

Address of Applicant :Assistant Professor, Department of Physics, IFTM University, Moradabad, Uttar Pradesh - 244102 Moradabad ------

2)Dr Richa Saxena

3)Mrs. Swati Gupta

4)Dr Kapil Pandey

5)Mr. Jitendra Pal Singh

Name of Applicant : NA

Address of Applicant : NA

(72)Name of Inventor:

1)Dr Narender Singh

Address of Applicant :Assistant Professor, Department of Physics, IFTM University, Moradabad, Uttar Pradesh - 244102 Moradabad

2)Dr Richa Saxena

Address of Applicant : Assistant Professor, Department of Physics, IFTM University, Moradabad, Uttar Pradesh - 244102 Moradabad

3)Mrs. Swati Gupta

Address of Applicant :Assistant Professor, Department of Physics, IFTM University, Moradabad, Uttar Pradesh - 244102 Moradabad

4)Dr Kapil Pandey

Address of Applicant :Assistant Professor, Department of Physics, IFTM University, Moradabad, Uttar Pradesh - 244102 Moradabad

5)Mr. Jitendra Pal Singh

Address of Applicant :Assistant Professor, Department of Physics, IFTM University, Moradabad, Uttar Pradesh - 244102 Moradabad

(57) Abstract:

The present invention relates to the organic solar cell has been simulated by GPVDM software at different device temperatures. This device model consists of mixture of P3HT and PCBM materials as active layer. In this device ITO is a transparent electrode, PEDOT: PSS is buffer layer and Al is a back electrode. In this study the electrical simulation has been done at different device temperatures 270K, 290K, 320K, and 345K. It is observed that J-V characteristics are affected by the device temperature. We obtain maximum efficiency 5.2% at temperature 345K with active layer thickness 250 nm.

No. of Pages: 11 No. of Claims: 4